



PTO/SB/08A (08-03)

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Sheet 1 of 5

Complete if Known

Application Number	10/019,009
Filing Date	April 26, 2002
First Named Inventor	Victor B. Kley
Art Unit	2881
Examiner Name	T. Nguyen
Attorney Docket Number	020921-000710US

U.S. PATENT DOCUMENTS*

Examiner Initials*	Cite No.	Document Number Number Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
KN	1	6,353,219	03-05-2002	Kley	
	2	20020002682	01-24-2002	Park et al. This is not prior art.	
KN	3	6,340,613	01-22-2002	Tominaga et al.	
	4	6,337,479	01-08-2002	Kley	
	5	6,265,711	07-24-2001	Kley	
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	8	6,226,609	05-08-2001	Muramatsu et al.	
	9	6,144,026	11-07-2000	Kley	
	10	6,101,164	08-08-2000	Kado et al.	
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	12	6,031,756	02-29-2000	Ginsowski et al.	
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	15	5,674,725	02-23-1999	Haydon	
	16	5,665,978	02-02-1999	Cohen	
	17	5,625,670	10-20-1998	Chernoff et al.	
	18	5,621,410	10-13-1998	Xiang et al.	
	19	5,763,879	06-09-1998	Zimmer et al.	
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KN	41	5,471,458	11-28-1995	Oguchi et al.	

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Sheet 2 of 5

Application Number	10/019,009
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First Named Inventor	Victor B. Kley
Art Unit	2881
Examiner Name	T. Nguyen
Attorney Docket Number	020921-000710US

U.S. PATENT DOCUMENTS+

Examiner Initials*	Cite No. ¹	Document Number Number Kind Code ² (If known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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	43	5,461,605	10-24-1995	Takimoto	
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	46	5,426,631	06-20-1995	Miyazaki et al.	
	47	5,416,363	05-23-1995	Elings et al.	
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	49	5,414,690	05-09-1995	Shido et al.	
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	53	5,398,483	03-07-1995	Matsida	
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	62	5,354,985	10-11-1994	Quate	
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Sheet 3 of 5

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Application Number	10/019,009
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First Named Inventor	Victor B. Kley
Art Unit	2881
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U.S. PATENT DOCUMENTS+

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		Number Kind Code ² (if known)			
CN	83	5,241,527	08-31-1993	Eguchi	
	84	5,231,286	07-27-1993	Kajimura et al.	
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	99	5,081,380	01-14-1992	Elings et al.	
	100	5,072,116	12-10-1991	Kawade et al.	
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	103	5,043,577	08-27-1991	Pohl	
	104	5,038,322	08-06-1991	Van Loenen	
	105	5,025,346	06-18-1991	Tang	
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	107	5,015,850	05-14-1991	Zdeblick	
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	115	4,831,614	05-16-1989	Duerig	
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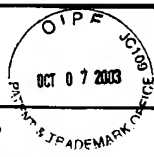
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Sheet 4 of 5

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First Named Inventor	Victor B. Kley
Art Unit	2881
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U.S. PATENT DOCUMENTS+

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		Number	Kind Code ² (if known)			
EN	124	3,586,865		06-22-1971	Baker et al.	

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Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	†*
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)				
EN	125	PCT	WO 01/03157		01-11-2001			
	126	PCT	WO 98/34082	A2	05-06-1996			
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	128	PCT	WO 96/03641	A1	02-06-1996			
	129	JP	7-105580		04-21-1995			
	130	JP	61-133065		06-20-1986			yes
	131	JP	1-262403		10-19-1969			abstract only
EN	132	EP	0325056		07-26-1989			abstract only

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Examiner Signature	K. Nguyen	Date Considered	12-07-03
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Sheet 5 of 5

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Application Number	10/019,009
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First Named Inventor	Victor B. Kley
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NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
W.N	133	AGER et al., "Multilayer hard carbon films with low wear rates," <i>Surface and Coatings Technology</i> , 91:91-94 (1997).	
	134	BETZIG et al "Near-Field Optics: Microscopy Spectroscopy and Surface Modification Beyond the Diffraction Limit" <i>Science</i> 257:(1992).	
	135	DAI et al. " Nanotubes as nanoprobe in scanning probe microscopy," <i>Nature</i> 384:147-150 (1998).	
	136	DAVIS "Deposition characterization and device development in diamond silicon carbide and gallium nitride thin films" <i>J. Vac. Sci. Technol. A</i> 11(4), Jul./Aug. (1993).	
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	138	GIVARGIZOV et al "Growth of diamond particles on sharpened silicon tips" <i>Materials Letters</i> 18:(1993).	
	139	GOMYUO, H., et al. Effect of Electrochemical Treatments on the Photoluminescence from Porous Silicon, <i>J. Electrochem. Soc.</i> , vol. 139, No. 9, Sep. 1992, pp. L86-L88.	
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	141	RASMUSSEN et al. "Fabrication of an All-metal Atomic Force Microscope Probe," <i>IEEE</i> (1987).	
	142	ROSSOW, U., et al., Influence of the Formation Conditions on the Microstructure of Porous Silicon Layers Studied by Spectroscopic Ellipsometry, <i>Thin Solid Films</i> , 256 (1995), pp. 5-8.	
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	144	TANG, William Chi-Keung, "Electrostatic comb drive for resonant sensor and actuator applications," Abstract of dissertation at the University of California at Berkeley (1990).	
	145	TOLEDO-CROW et al "Near-field differential scanning optical microscope with atomic force regulation" <i>Appl. Phys. Lett.</i> 60: (1992).	
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Examiner Signature	K. NGUYEN	Date Considered	12-07-03
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